TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

# 2SK3302

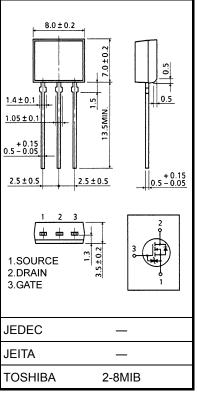
### Switching Regulator and DC-DC Converter Applications

Unit: mm

- Low drain-source ON resistance: RDS (ON) =  $11.5 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 0.4 \text{ S (typ.)}$
- Low leakage current:  $I_{DSS} = 100 \mu A \text{ (max) (V}_{DS} = 500 \text{ V)}$
- Enhancement model:  $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit		
Drain-source voltage		$V_{DSS}$	500	V		
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	500	V		
Gate-source voltage			V <sub>GSS</sub>	±30	V	
Drain current	DC (Note	e 1)	I <sub>D</sub>	0.5	Α	
	Pulse (Note	e 1)	I <sub>DP</sub>	1.5	A	
Drain power dissipation			P <sub>D</sub>	1.3	W	
Single pulse avalanche energy (Note 2)			E <sub>AS</sub>	14.3	mJ	
Avalanche current			I <sub>AR</sub>	0.5	Α	
Repetitive avalanche energy (Note 3)			E <sub>AR</sub>	0.13	mJ	
Channel temperature			T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C		



Weight: 1.9 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	96.1	°C/W

- Note 1: Ensure that the channel temperature does not exceed 150°C.
- Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$ , L = 100 mH,  $R_G = 25 \Omega$ ,  $I_{AR} = 0.5 \text{ A}$
- Note 3: Repetitive rating: pulse width limited by maximum channel temperature.

This transistor is an electrostatic-sensitive device. Please handle with caution.



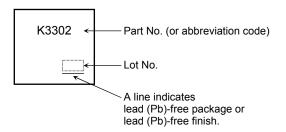
## **Electrical Characteristics (Ta = 25°C)**

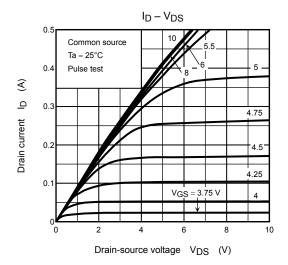
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Gate-source brea	kdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{GS} = 0 \ V$	±30	_	_	V
Drain cut-OFF cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V	_	_	100	μА
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	500	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.25 A	_	10	18	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 0.25 A	0.2	0.4	_	S
Input capacitance	)	C <sub>iss</sub>		_	75	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	7	_	pF
Output capacitance		Coss		_	24	_	
Rise time  Turn-ON time  Fall time  Turn-OFF time	Rise time	t <sub>r</sub>	$V_{GS} = 0.25 \text{ A}$ $V_{GS} = 0.25 \text{ A}$ $V_{DD} \approx 250 \text{ V}$ $V_{DD} \approx 250 \text{ V}$ $V_{DD} \approx 250 \text{ V}$	_	11	_	- ns
	Turn-ON time	t <sub>on</sub>			18	_	
	Fall time	t <sub>f</sub>			54	_	
	Turn-OFF time	t <sub>off</sub>		_	95	_	
Total gate charge (gate-source plus gate-drain)		Qg			3.8		nC
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 0.5 \text{ A}$	_	1.9	_	
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	1.9	_	

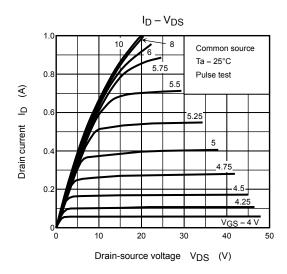
# **Source-Drain Ratings and Characteristics (Ta = 25°C)**

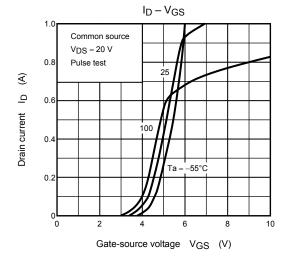
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	$I_{DR}$	_	_	_	0.5	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	1.5	Α
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.5	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 0.5 \text{ A}, V_{GS} = 0 \text{ V},$	_	190	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 100 A/μs		380	_	nC

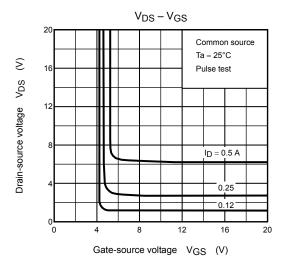
# Marking

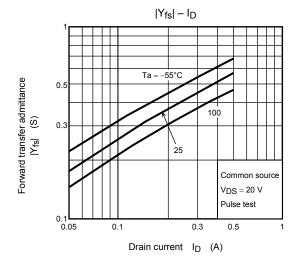


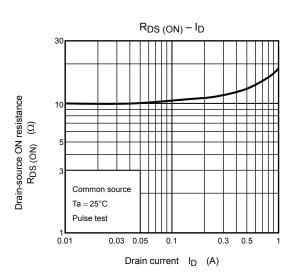




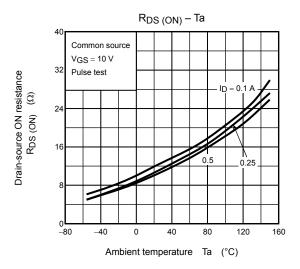


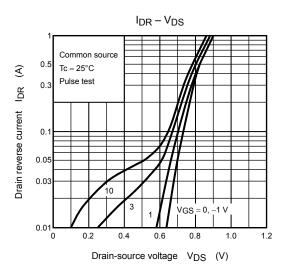


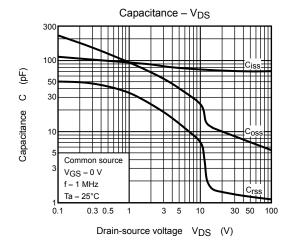


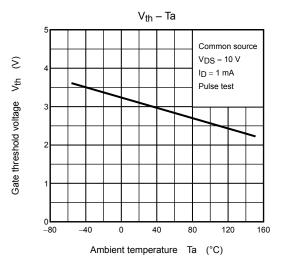


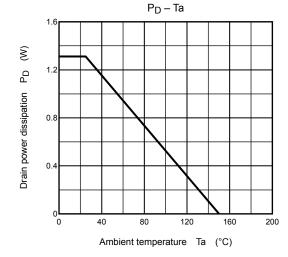
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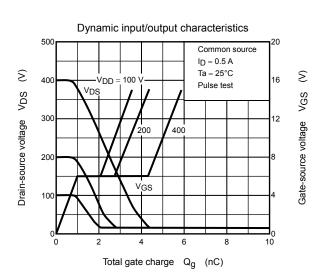


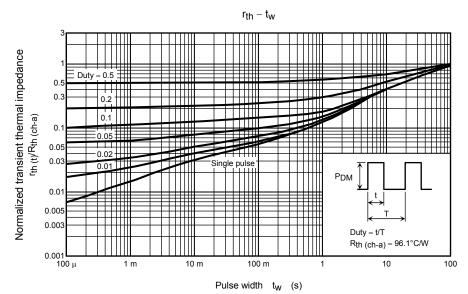




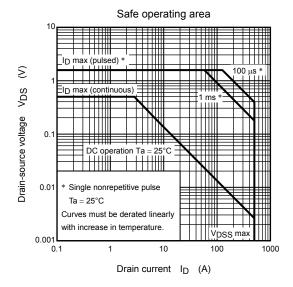


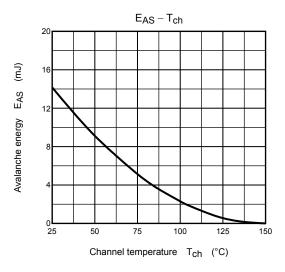


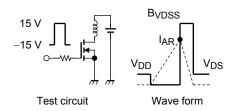












$$R_G = 25~\Omega$$
 
$$V_{DD} = 90~V,~L = 100~mH$$

$$\mathsf{E}_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{\mathsf{B}_{VDSS}}{\mathsf{B}_{VDSS} - \mathsf{V}_{DD}} \right)$$

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